

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/614,316 ARORA ET AL.	
		Examiner	Art Unit	Page 1 of 1 Shefali D. Patel 2624

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*	C	US-6,560,354	05-2003	Maurer et al.	382/131
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.